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## The First IEEE International Workshop on Electronic Design, Test and Applications (DELTA 2002)

Michel Renovell, Seiji Kajihara, Ibrahim Ai-Bahadly, Serge Demidenko

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Proceedings

The First IEEE International Workshop on  
**Electronic Design, Test and Applications**



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The First IEEE International Workshop on  
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Edited by

M. Renovell, S. Kajihara, I. Al-Bahadly and S. Demidenko

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